

PENDING CLAIMS

The following is a list of currently pending claims. Claims 2, 9, 15, and 17-19 are amended as shown. Claim 14 is cancelled.

1. (Cancelled)
2. (Currently amended) The method of claim 17 wherein the temperature is ~~between about 450 and less than or~~ about 480 degrees Celsius.
3. (Original) The method of claim 2 wherein pressure is between about 200 mTorr and about 1 Torr.
4. (Original) The method of claim 3 wherein an inert gas is flowed over the surface with the SiH₄ and BCl₃.
5. (Original) The method of claim 4 wherein the inert gas is helium.
6. (Cancelled)
7. (Previously amended) The method of claim 18, wherein the second source gas comprises about 0.1 percent BCl₃ or more.
8. (Original) The method of claim 7, wherein the second source gas further comprises an inert gas.
9. (Currently amended) The method of claim 8, wherein the temperature is ~~between about 450 less then or~~ about 480 degrees Celsius.
10. (Original) The method of claim 9, wherein the inert gas is helium.

11. (Original) The method of claim 8, wherein the pressure is between about 200 mTorr and about 1 Torr.
12. (Cancelled)
13. (Currently amended) The method of claim 19 wherein the step of depositing the polysilicon film comprises substantially simultaneously flowing SiH₄ and BCl₃ over the surface.
14. (Cancelled)
15. (Currently amended) The method of claim 14 13 wherein the temperature is ~~between about 450 and less than or~~ about 480 degrees Celsius.
16. (Original) The method of claim 15 wherein the pressure is between 200 mTorr and 1 Torr.
17. (Currently amended) A method for depositing a doped polysilicon film comprising:
providing a surface; and
substantially simultaneously flowing SiH₄ and BCl₃ over the surface at a temperature ~~less than or equal to between about 460 and~~ about 500 degrees Celsius under conditions that achieve an average concentration in the doped polysilicon film of between about 7×10^{20} and about 3×10^{21} boron atoms per cubic centimeter, wherein the doped polysilicon film is polycrystalline as deposited.
18. (Previously added) A method for forming an in-situ doped polysilicon film, the method comprising:
providing a surface; and

substantially simultaneously flowing a first source gas comprising SiH₄ and a second source gas comprising BCl₃ over the surface at a temperature ~~less than~~ between about 460 and about 500 degrees Celsius under conditions sufficient to achieve in the doped polysilicon an average concentration of between about 7 x 10²⁰ and about 3 x 10²¹ boron atoms per cubic centimeter, wherein during this flowing step, polycrystalline silicon is deposited.

19. (Currently amended) A method for depositing an in-situ doped polysilicon film comprising:
 - providing a substrate comprising a substantially horizontal surface and a substantially vertical sidewall descending from the horizontal surface, the sidewall having a top; and
 - depositing the in-situ doped polysilicon film on the surface at a temperature ~~less than~~ between about 460 and about 500 degrees Celsius, wherein:
 - a first thickness of the film at its thinnest point on the vertical sidewall is at least 80 percent of a second thickness of the film on the sidewall at the top of the sidewall, and
 - a third thickness of the film on the horizontal surface is at least 200 angstroms,
 - wherein an average concentration of boron atoms in the polysilicon is between about 7 x 10²⁰ and about 3 x 10²¹ per cubic centimeter, and wherein, during the depositing step, doped polycrystalline silicon is deposited.

CLAIM AMENDMENTS

Independent claims 17, 18, and 19 have all been amended to recite a temperature range between 460 degrees C and 500 degrees C. Support for this amendment can be found, *inter alia*, at paragraph [0028].

Claims 2, 9, and 15 have been amended to recite that the deposition temperature is less than or about 480 degrees C. Support for this claim can be found at paragraph [0035].

Independent claim 19 has been amended to include the limitation of its dependent claim 14, which has been cancelled.

Claim 15 has been amended to depend from claim 13 rather than from cancelled claim 14.

None of these claim amendments constitutes new matter.